Product data sheet

1. General description

Planar passivated Silicon Controlled Rectifier (SCR) in a TO220 plastic package intended for use in applications requiring very high inrush current capability, high thermal cycling performance and high junction temperature capability ($T_{i(max)} = 150$ °C).

2. Features and benefits

- High junction operating temperature capability ($T_{j(max)} = 150 \, ^{\circ}\text{C}$)
- Very high current surge capability
- · Planar passivated for voltage ruggedness and reliability
- High turn-on current rise dl_T/dt = 150 A/μs
- High noise immunity dV_D/dt = 500 V/µs up to 150 °C
- · High thermal cycling performance
- · High voltage capability

3. Applications

- · High voltage capability
- · Protection circuits e.g. SMPS inrush current
- Motor control circuits and starters
- Voltage regulation
- Solid state relays

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes		Values		Unit
V_{DRM}	repetitive peak off-state voltage				800		V
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{mb} \le 125 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3			50		А
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25$ °C; $t_p = 10$ ms; Fig. 4; Fig. 5			500		А
		half sine wave; $T_{j(init)}$ = 25 °C; t_p = 8.3 ms			550		А
T _j	junction temperature				-40 to 15	50	°C
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static cha	aracteristics						
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7$		-	-	15	mA
I _H	holding current	$V_D = 12 \text{ V}; \ T_j = 25 \text{ °C}; \underline{\text{Fig. 9}}$		-	-	60	mA
V _T	on-state voltage	I _T = 100 A; T _j = 25 °C; <u>Fig. 10</u>		-	-	1.65	V
Dynamic	characteristics				,		
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_{j} = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		500	-	-	V/µs

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode	mb	. 51
2	А	anode		A K G
3	G	gate		sym037
mb	A	mounting base; connected to anode		

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
TYN50-800T	TO220	TYN50-800TQ	Tube	50	SOT78	13-Jun-2008

7. Marking

Table 4. Marking codes

Type number	Marking codes
TYN50-800T	TYN50
	800T

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
V_{DRM}	repetitive peak off-state voltage			800	V
V_{RRM}	repetitive peak reverse voltage			800	V
I _{T(AV)}	average on-state current	half sine wave; T _{mb} ≤ 125 °C;		32	А
$I_{T(RMS)}$	RMS on-state current	half sine wave; T _{mb} ≤ 125 °C; Fig. 1; Fig. 2; Fig. 3		50	А
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 10 ms; Fig. 4; Fig. 5		500	А
		half sine wave; $T_{j(init)} = 25 ^{\circ}\text{C}$; $t_p = 8.3 \text{ms}$		550	А
l ² t	I ² t for fusing	t _p = 10 ms; sine-wave pulse		1250	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 30 mA		150	A/µs
I _{GM}	peak gate current			5	А
V_{GM}	peak gate voltage			5	V
P_{GM}	peak gate power			20	W
$P_{G(AV)}$	average gate power	over any 20 ms period		1	W
T_{stg}	storage temperature			-40 to 150	°C
T _j	junction temperature			-40 to 150	°C

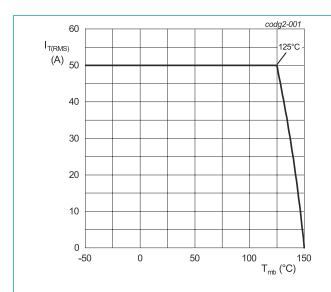
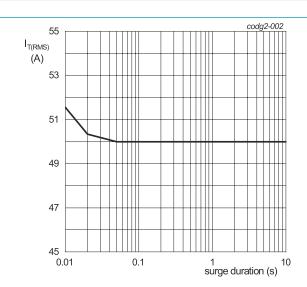
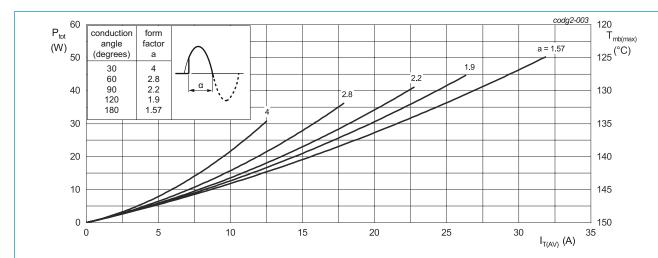


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



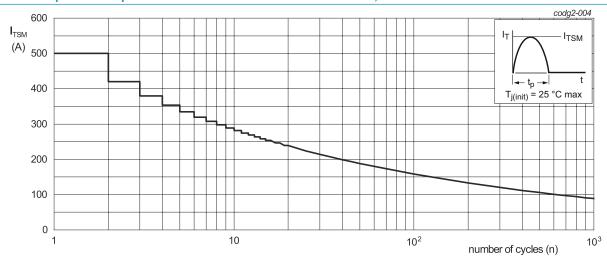
f = 50 Hz; T_{mb} = 125 °C Fig. 2. RMS on-state current as a function of surge duration; maximum values



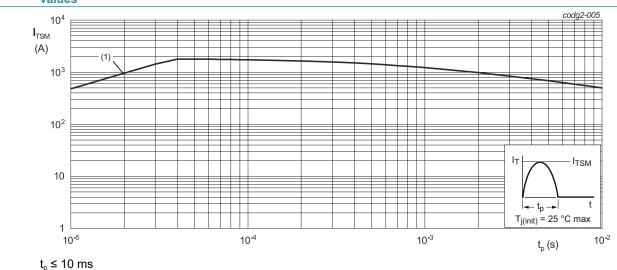
 α = conduction angle

a = form factor = $I_{T(RMS)}/I_{T(AV)}$

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz
 Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



(1) dl_⊤/dt limit

Fig. 5. Non-repetitive peak on-state current as a function of pulse duration; maximum values

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SCR

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. 6		-	-	0.5	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	in free air		-	60	-	K/W

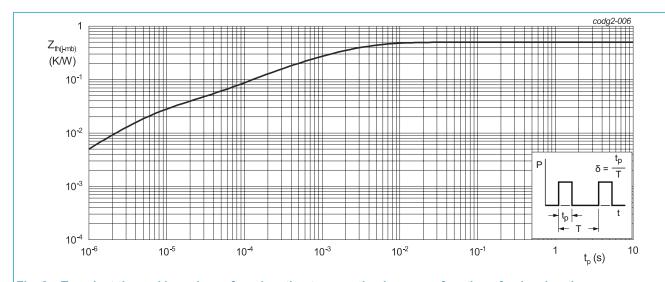


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
	racteristics	Conditions	110100		.,,,,,	III GA	
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_i = 25 \text{ °C}; Fig. 7$		-	_	15	mA
IL	latching current	V _D = 12 V; I _G = 0.1 A; T _j = 25 °C; <u>Fig. 8</u>		-	-	80	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>		-	-	60	mA
V _T	on-state voltage	I _T = 100 A; T _j = 25 °C; <u>Fig. 10</u>		-	-	1.65	V
$V_{\rm GT}$	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 11$		-	0.7	1.2	V
		V _D = 400 V; I _T = 0.1 A; T _j = 150 °C		0.25	0.5	-	V
I _D	off-state current	V _D = 800 V; T _j = 25 °C		-	-	5	μA
		V _D = 800 V; T _j = 150 °C		-	-	2	mA
I _R	reverse current	V _D = 800 V; T _j = 25 °C		-	-	5	μA
		V _D = 800 V; T _j = 150 °C		-	-	2	mA
Dynamic	characteristics						
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_{j} = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		500	-	-	V/µs
t _{gt}	gate-controlled turn-on time	$I_{TM} = 50 \text{ A}; V_D = 800 \text{ V}; I_G = 30 \text{ mA};$ $dI_G/dt = 5 \text{ A}/\mu\text{s}; T_j = 25 ^{\circ}\text{C}$		-	2	-	μs
t _q	commutated turn-off time	$I_{TM} = 2 \text{ A}; t_p = 50 \mu\text{s}; dV/dt = 5 V/\mu\text{s}; dI/dt = 30 A/\mu\text{s}; T_j = 25 ^{\circ}\text{C}$		-	-	25	μs

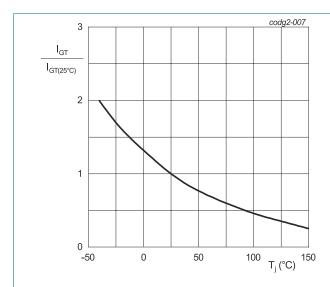


Fig. 7. Normalized gate trigger current as a function of junction temperature

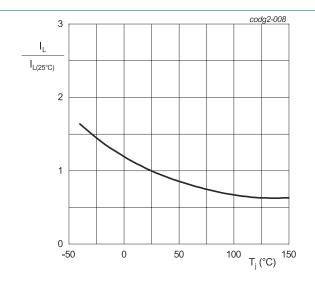


Fig. 8. Normalized latching current as a function of junction temperature

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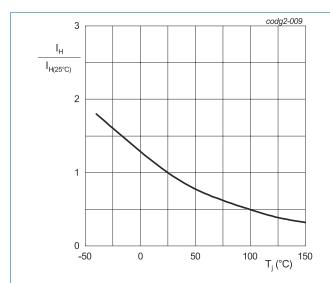
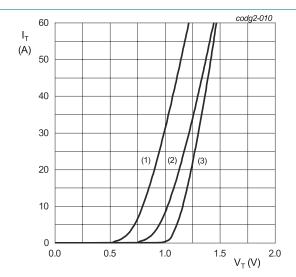


Fig. 9. Normalized holding current as a function of junction temperature



 $V_o = 1.006 \text{ V}; R_s = 0.0073 \Omega$ (1) T_j = 150 °C; typical values (2) T_j = 150 °C; maximum values (3) $T_j = 25$ °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

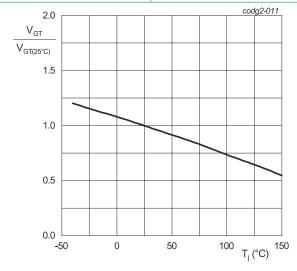
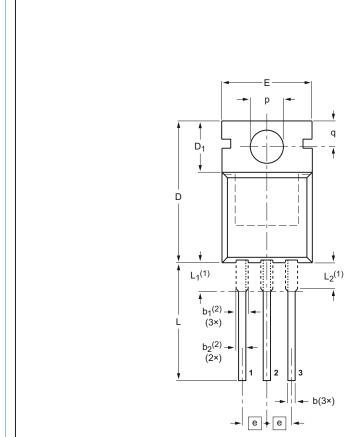


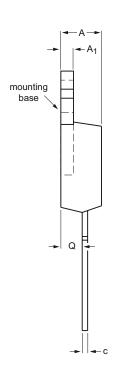
Fig. 11. Normalized gate trigger voltage as a function of junction temperature

SOT78

11. Package outline



Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB



0 5 10 mm scale

DIMENSIONS (mm are the original dimensions)

UN	IIT	Α	A ₁	b	b ₁ ⁽²⁾	b ₂ ⁽²⁾	С	D	D ₁	E	е	L	L ₁ ⁽¹⁾	L ₂ ⁽¹⁾ max.	р	q	Q
m	m	4.7 4.1	1.40 1.25	0.9 0.6	1.6 1.0	1.3 1.0	0.7 0.4	16.0 15.2	6.6 5.9	10.3 9.7	2.54	15.0 12.8	3.30 2.79	3.0	3.8 3.5	3.0 2.7	2.6 2.2

- Lead shoulder designs may vary.
 Dimension includes excess dambar.

OUTLINE	JTLINE REFERENCES		EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT78		3-lead TO-220AB	SC-46		08-04-23 08-06-13

12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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